

Search Notes

Application/Control No.

10/517,517

Examiner

Seung H. Lee

Applicant(s)/Patent under
Reexamination

DEMMELE ET AL.

Art Unit

2887

SEARCHED

Class	Subclass	Date	Examiner
235	379	1/18/2008	SL
235	380	1/18/2008	SL
705	45	1/18/2008	SL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same as	Above	1/18/2008	SL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/18/2008	SL
PCT cites	1/18/2008	SL